

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/767,514	GUEST, JOHN DEREK	
Examiner		Art Unit	3679	Page 1 of 1
David E. Bochna				

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-			
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NON-PATENT DOCUMENTS

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